

**Notice of References Cited**

Application/Control No.

09/294,563

Applicant(s)/Patent Under

Reexamination

SCHMIDT ET AL.

Examiner

Duc Nguyen

Art Unit

2643

Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,292,539	09-2001	Eichen et al	
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Testing in the unbundled loop: the challenge for ILECs & CLECs, copyright 1997, Harris Corporation, pages 7-8
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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